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Sheet Lof 1 FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE ATTY, DOCKET NO. SERIAL NO. (REV. 7-80) PATENT AND TRADEMARK OFFICE 10/010,199 ... 010544 HON 2 4 200 INFORMATION DISCLOSURE APPLICANT STATEMENT BY APPLICANT (Use several sheets if necessary) Butler et al. **GROUP** FILING DATE 2184-2133 DATE MAILED: November 19, 2003 December 4, 2001 **U.S. PATENT DOCUMENTS** FILING DATE **EXAMINER** Ref CLASS SUB INITIAL No **DOCUMENT NUMBER** DATE NAME IF APPRO-CLASS PRIATE Αl A2 Α3 A4 FOREIGN PATENT DOCUMENTS **EXAMINER** Ref DOCUMENT NUMBER DATE COUNTRY NAME CLASS **SUB** INITIAL No CLASS Digital Equipment G11B 0 4 0 7 0 1 **A2** 01/09/91 **EP** 20/18 DG **B**1 Corp. B2 В3 OTHER PRIOR ART (Including Author, Title, Date, Pertinent Page, Etc.) Katayama, Y et al: "One-Shot Reed-Solomon Decoding For High-Performance C1 Dependable Systems", 2000 IEEE International Networks, NY, USA, June 25, 2000, pages 390-399. Alzahrani, F et al: "On-Chip TEC-QED ECC For Ultra-Large, Single-Chip C2 Memory Systems", Proceedings IEEE International Conference On Computer Design, October 10, 1994, pages 132-137. Franklin, M et al: "Theory and Techniques For Testing Check Bits Of Rams With **C**3 On-Chip ECC", IEICE Transactions On Information and Systems, Tokyo, Japan, Volume E76-D, No. 10, October 1, 1993, pages 1243-1252. Nagvajara, P: "Multichip Module Diagnosis, Electro/94 International Conference C4 Proceedings, Boston, MA, IEEE, USA. Combined Volumes, May 10, 1994, pages 793-802. **DATE CONSIDERED EXAMINER** *EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.